

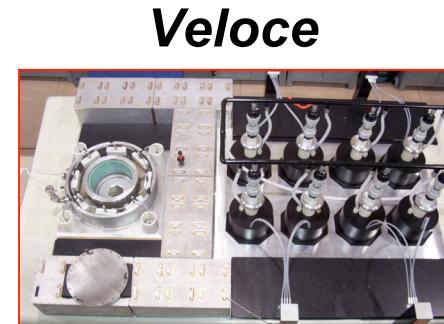
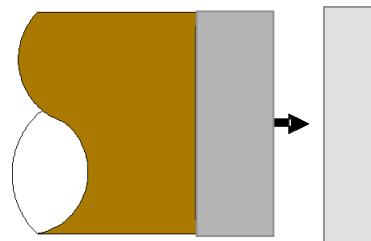
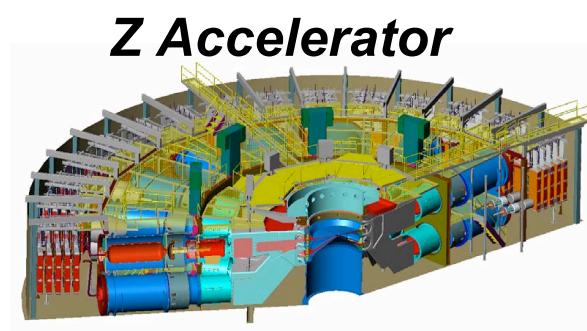


PDV measurements of structured wave profiles at modest velocities (< 1km/s)

SAND2009-7665C

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1646 Dynamic Material Properties



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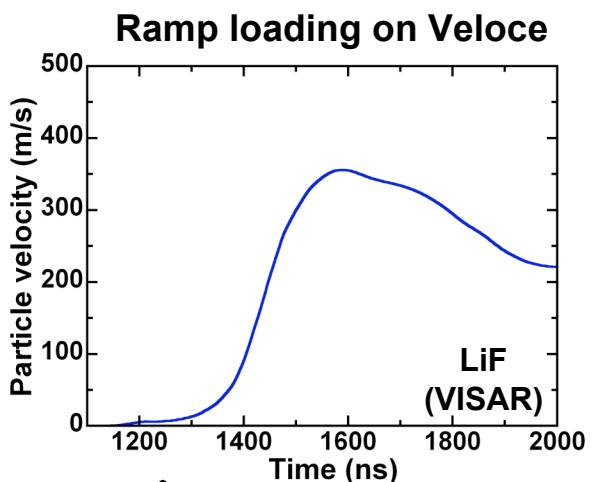
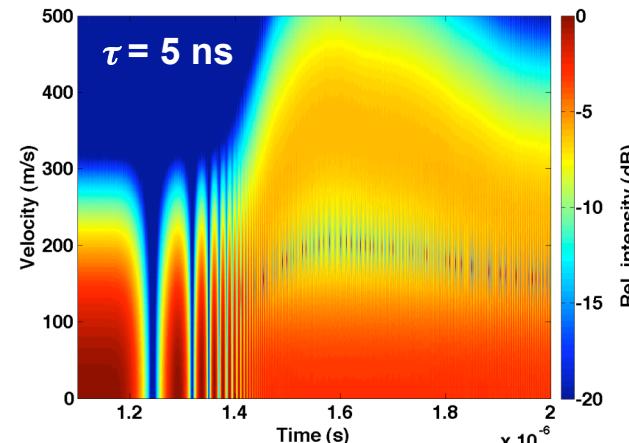
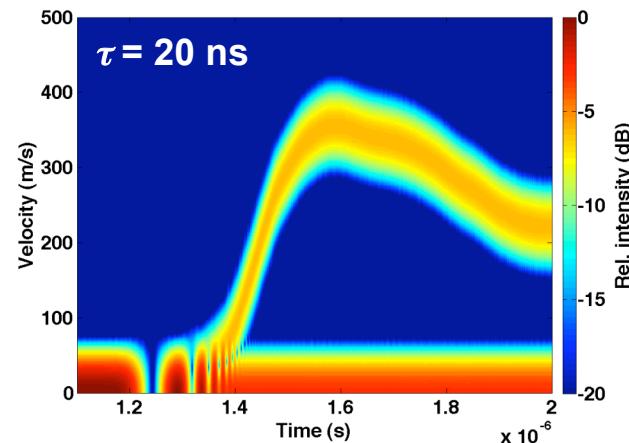
Purpose of Work

■ Background

- PDV beat frequency: $f = \frac{2v}{\lambda_0}$; uncertainty principle: $(\delta v)(\tau) \geq \frac{\lambda_0}{8\pi}$, $\tau = \frac{\lambda_0}{8\pi\delta v}$

■ Motivation

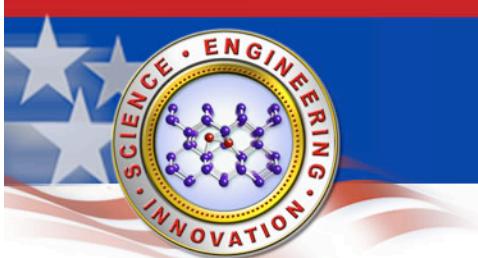
- Achieve both optimal velocity & time precision
- Where does this matter?
 - $v = 100 \text{ m/s}$, $\delta v \leq 10 \text{ m/s}$, $\tau = 6 \text{ ns}$, $f = 0.13 \text{ GHz}$
- “Modest” velocity (<1km/s) transients
 - Structured waves (ramps and multiple shocks)
 - Elastic precursors, phase transitions



**STFT
analysis**



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PDV Analyses

- **Detector measures output intensity**

$$D(t) = aI_R + bI_T(t) + 2\sqrt{I_R I_C(t)} \cos \left[\Phi(t_i) + 4\pi \frac{x(t) - x(t_i)}{\lambda_0} \right]$$

- **Short-time Fourier Transform (STFT)**

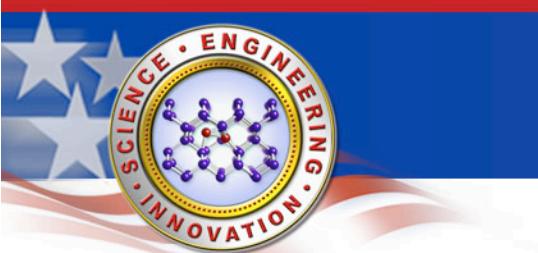
- Finite time window
- Velocity from Gaussian fitting of power spectrum

- **Three-phase analysis (THRIVE)**

- Three signals shifted by 120°
- Displacement from quadrature reduction (similar to VISAR analysis)
- Velocity from differentiation of displacement

- **Local sinusoid**

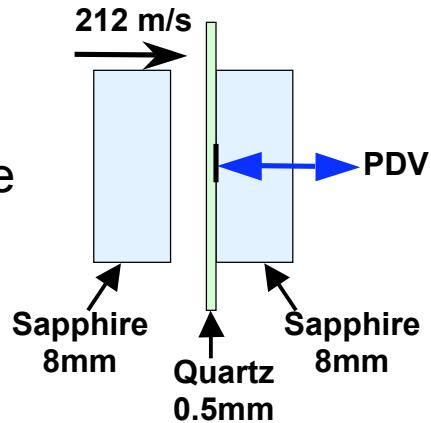
- Similar to STFT, less robust to transients



Experimental Configuration

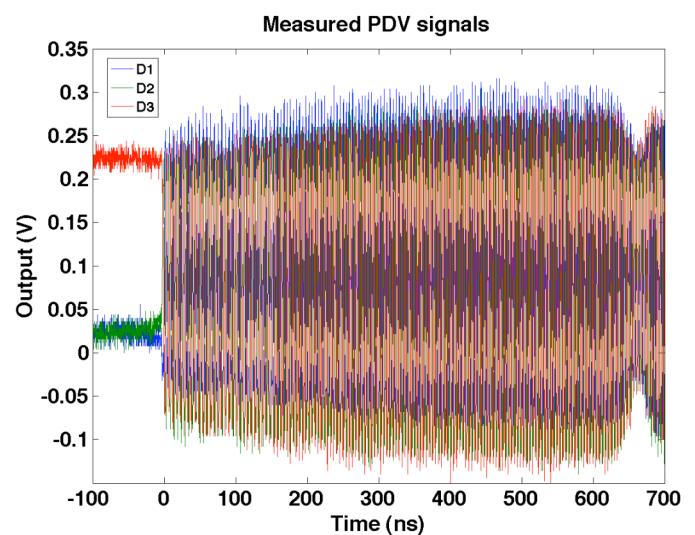
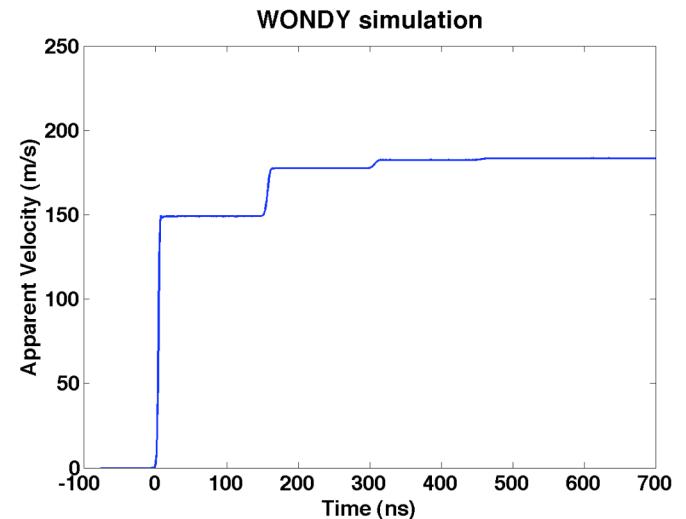
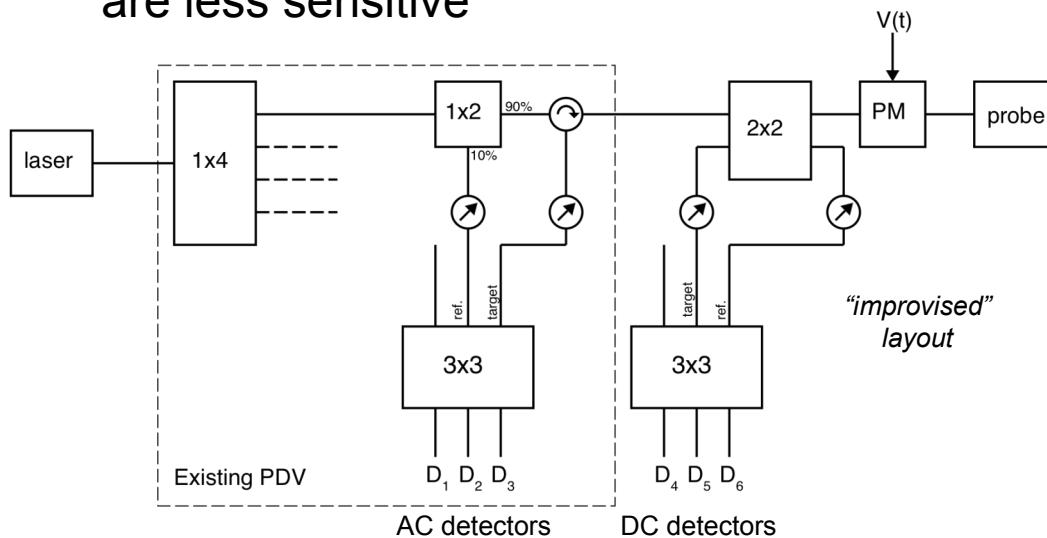
■ Gas gun

- Ring-up to shock state



■ Three-phase PDV measurement

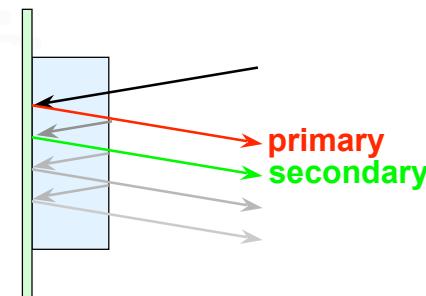
- Focusing probe ($f = 12$ mm)
- DC detectors cleaner than AC detectors but are less sensitive



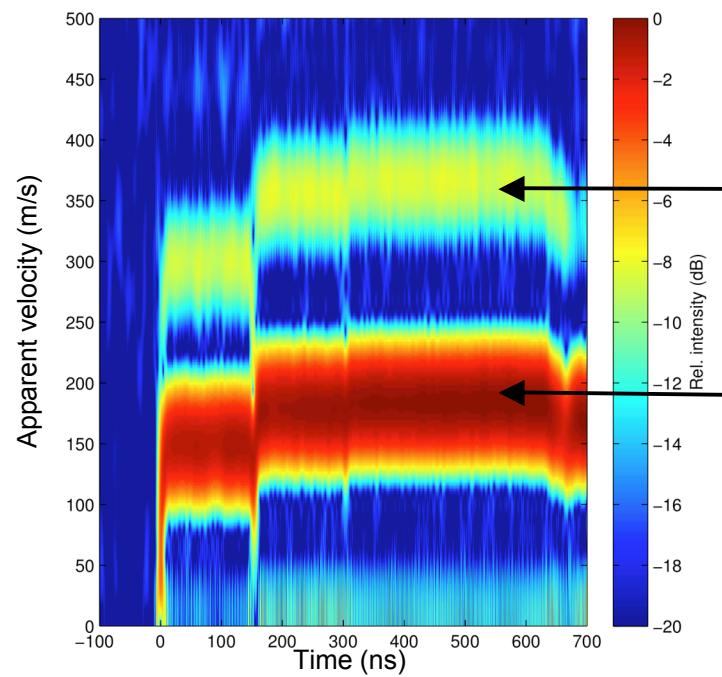
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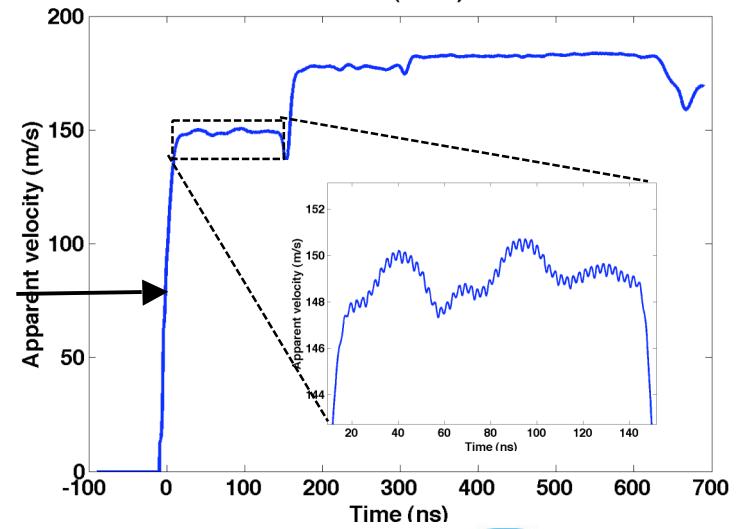
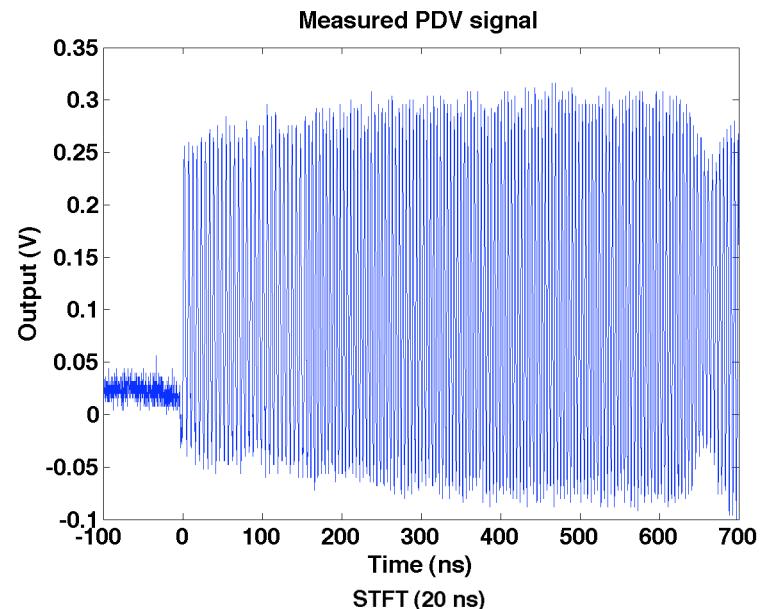
PDV01 – STFT Analysis



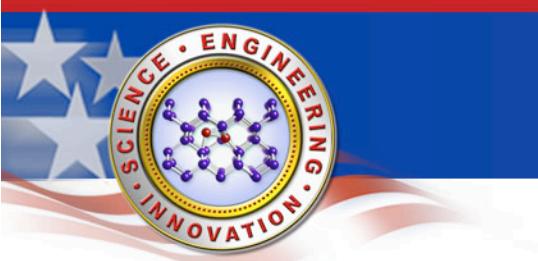
- **STFT power spectrum**
 - 20 ns Hamming window
 - Gaussian fitting of peaks



secondary reflection
primary reflection



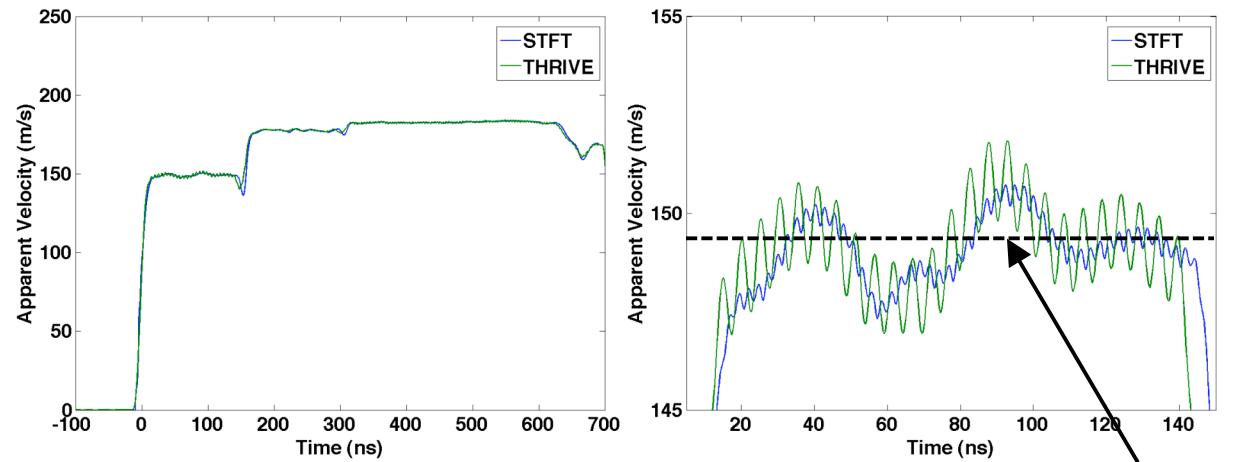
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PDV01 – THRIVE Analysis

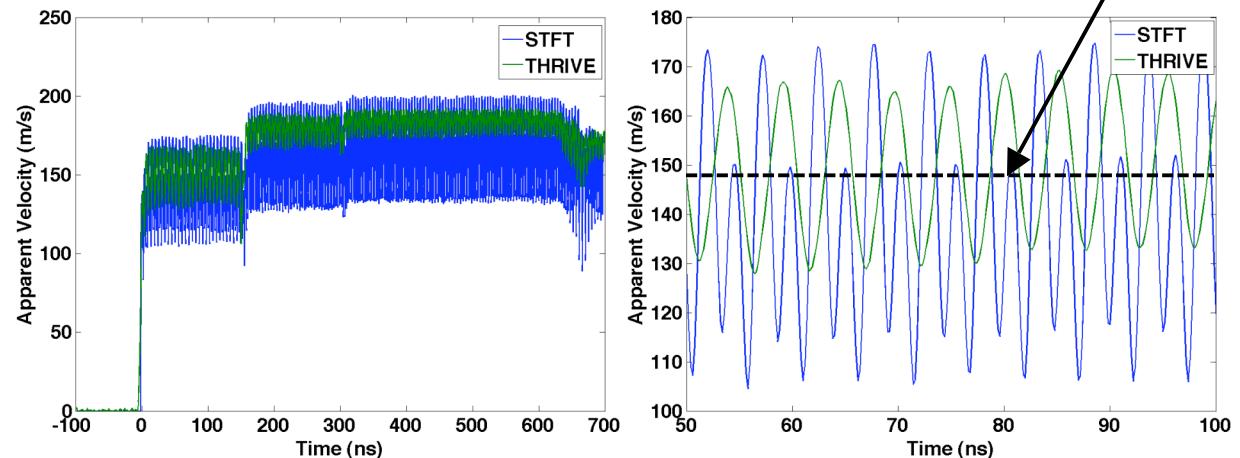
■ $\tau = 20$ ns

- THRIVE & STFT agree with WONDY prediction
- Smaller oscillations with STFT



■ $\tau = 5$ ns

- Deviation between THRIVE & STFT
- STFT's average velocity biased systematically lower than WONDY
- Smaller oscillations with THRIVE



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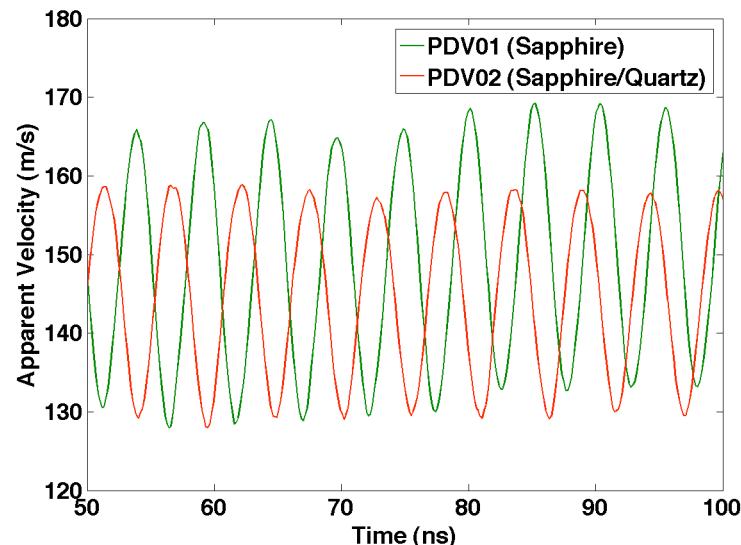
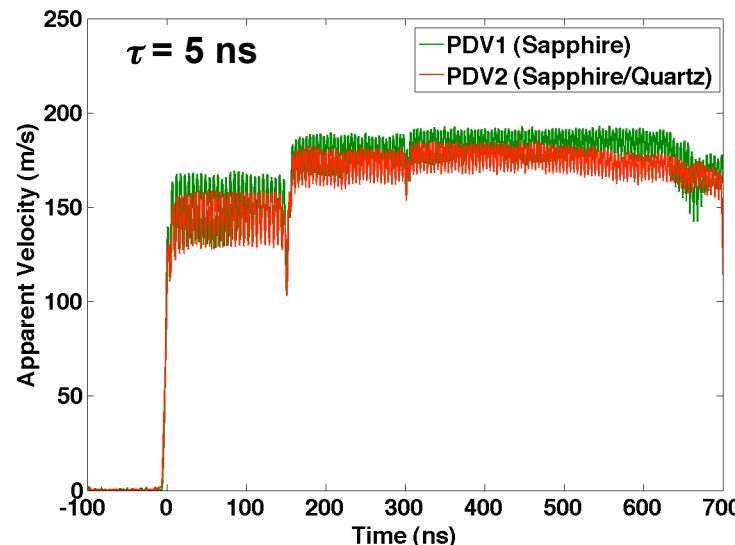
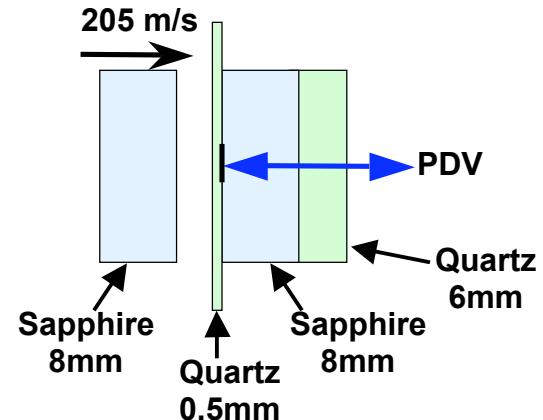


PDV02

■ Attempt to reduce secondary reflection

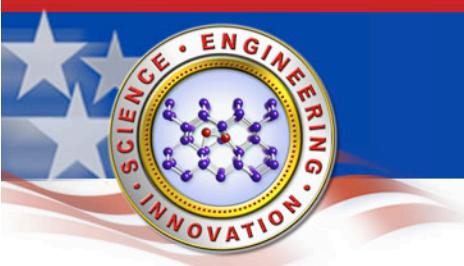
- Focusing probe insufficient
- Add Quartz window to diminish multiple window transit effect

$$D(t) \propto \sqrt{I_R I_{C1}(t)} \cos \Phi_1 + \sqrt{I_R I_{C2}(t)} \cos \Phi_2$$



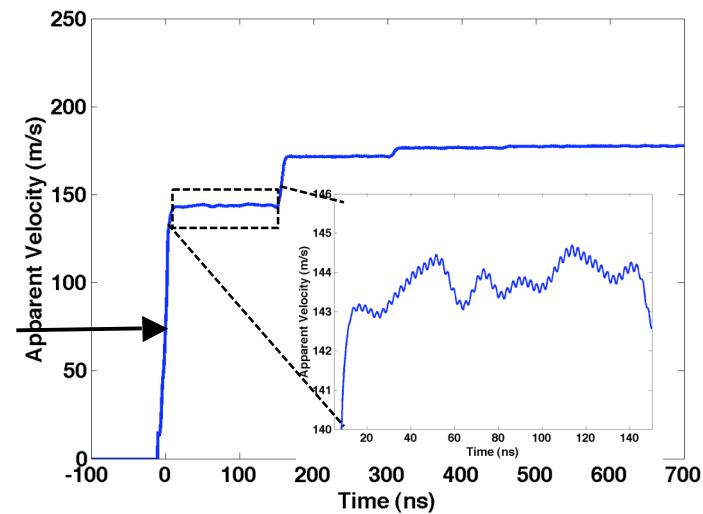
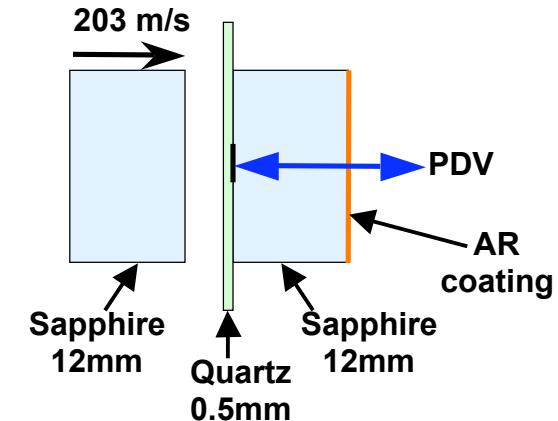
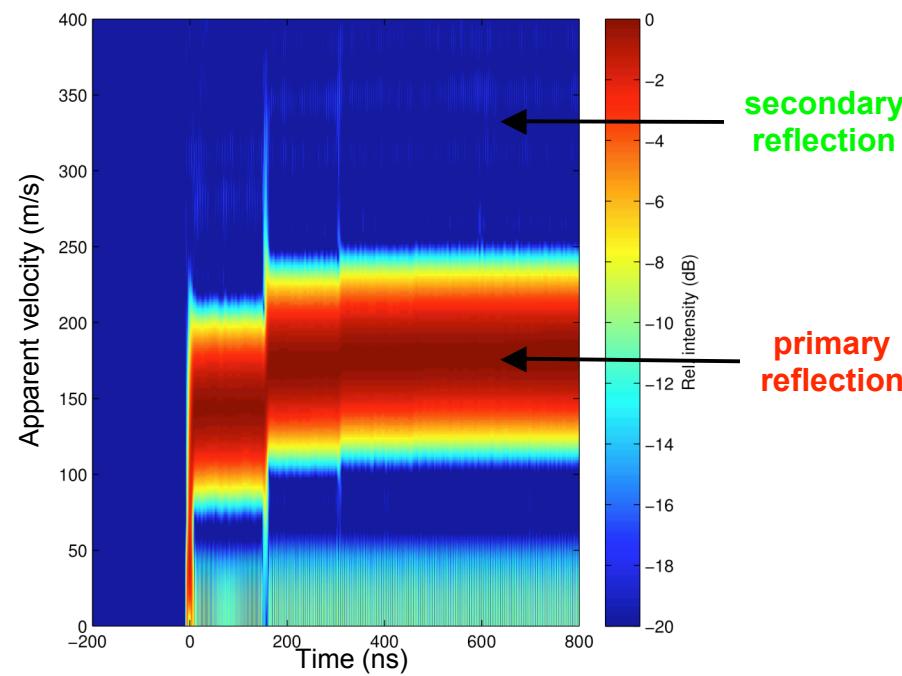
■ Oscillations smaller than with only Sapphire window but remains

- Need anti-reflective coating at free surface

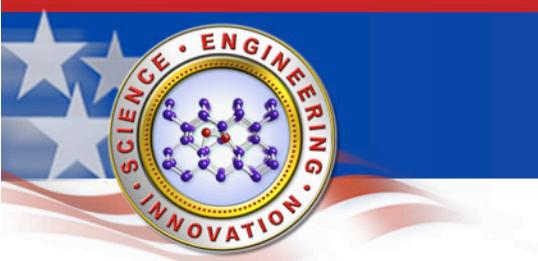


PDV03 – STFT Analysis

- **Anti-reflective coating**
 - < 0.05% at 1550 nm
- **STFT power spectrum**
 - 20 ns Hamming window
 - Gaussian fitting of peaks



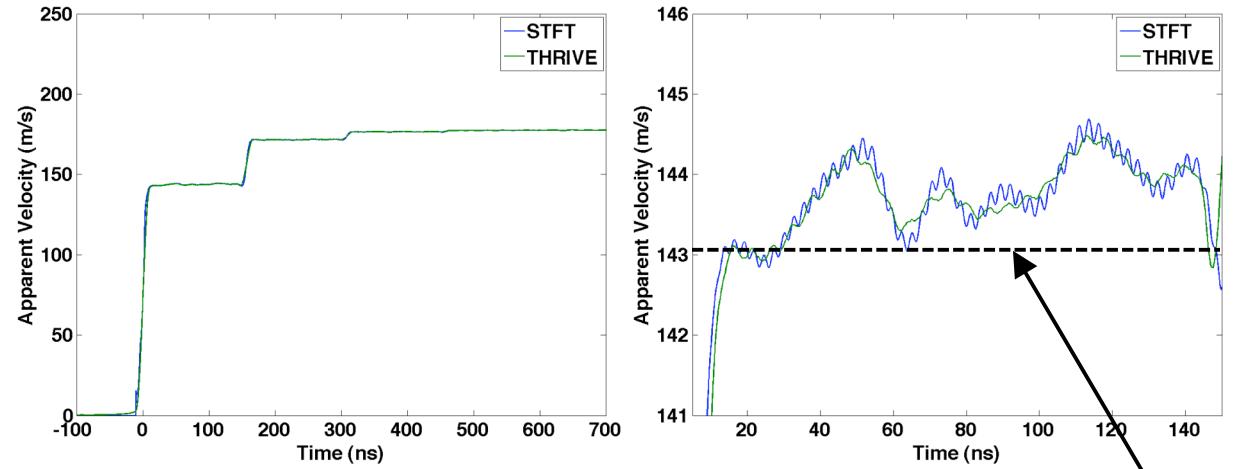
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PDV03 – THRIVE Analysis

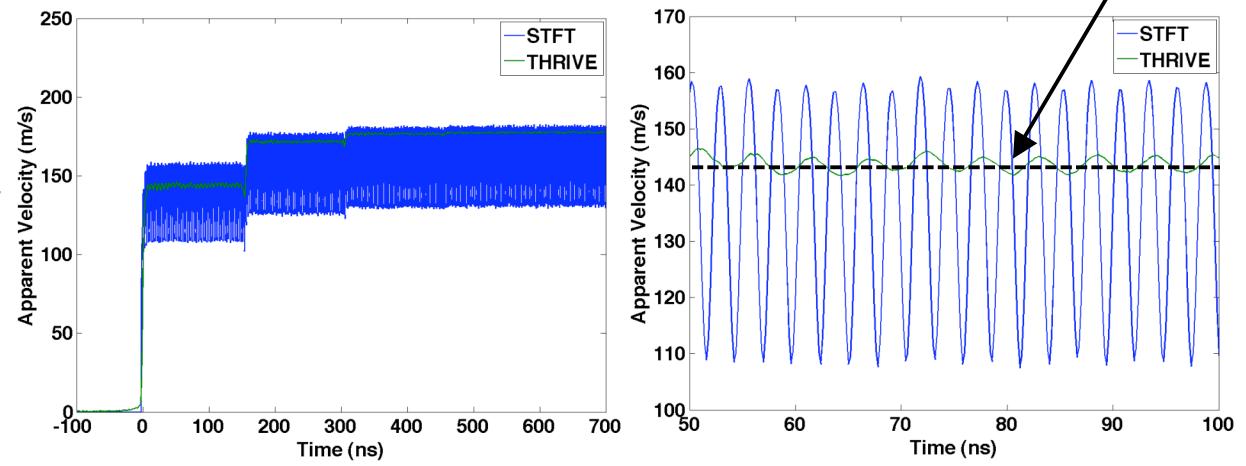
■ $\tau = 20$ ns

- THRIVE & STFT agree with WONDY prediction
- Smaller oscillations with STFT



■ $\tau = 5$ ns

- Deviation between THRIVE & STFT
- STFT's average velocity biased systematically lower than WONDY
- Smaller oscillations with THRIVE

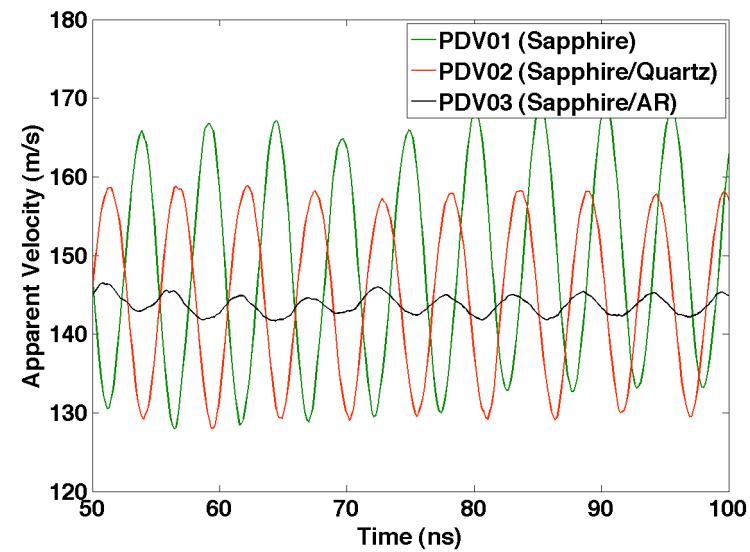
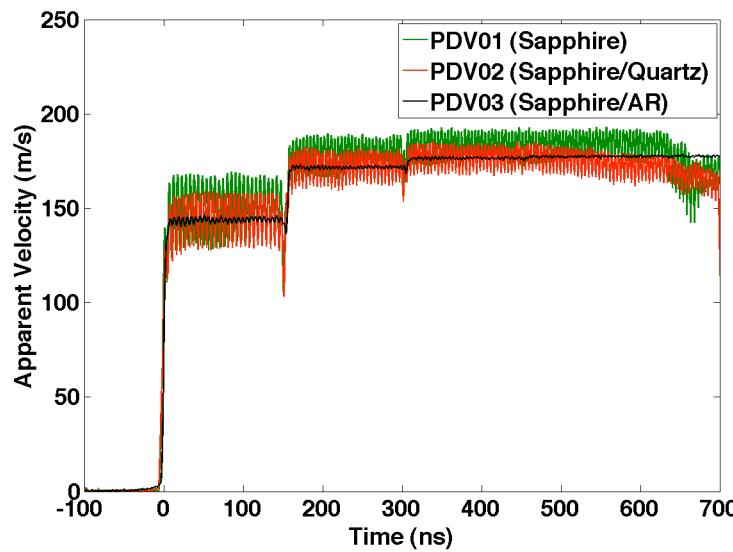


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Mitigation of secondary reflection

- Anti-reflective coating with THRIE analysis
 - Velocity oscillations of $\delta v/v = 1\% (1\sigma)$ and $\tau = 5 \text{ ns}$
 - Comparable to velocity and time precision of VISAR





Summary

- **Transient wave profiles at modest velocities**
 - Require optimization of both velocity and time precision
- **Short time Fourier Transform analysis (STFT)**
 - Robust and “simple”
 - Reliable over many fringes but suspect for small number of fringes
- **Three-phase analysis (THRIVE)**
 - More complicated (3 detectors/probe), more characterizations
 - Better for rapid transients
 - Consistent with STFT over many fringes
- **Must mitigate secondary reflection of window free surface**
 - Anti-reflective coating $< 0.05\%$
 - Wedged window



Extra Slides



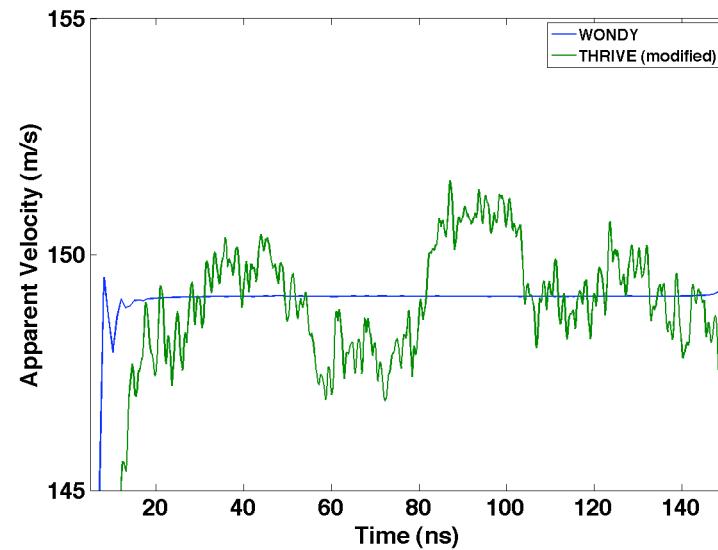
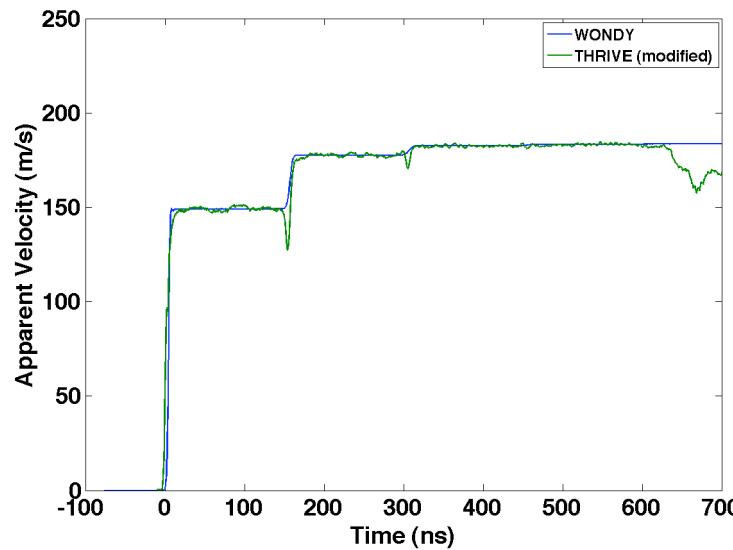
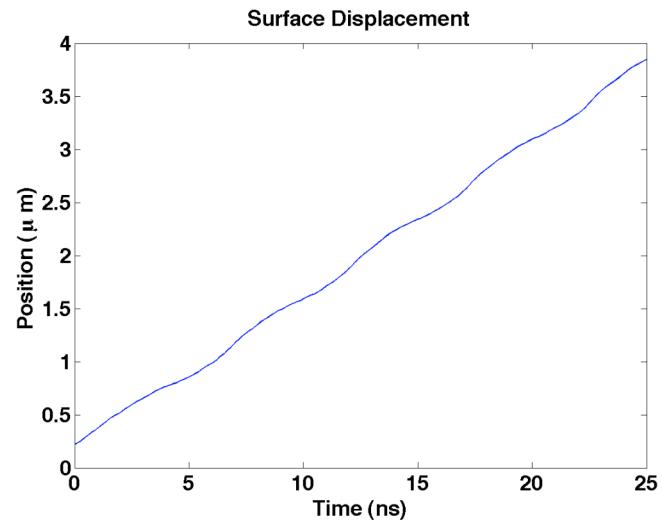
PDV01 – Displacement Analysis

- Examine displacement profile

- Sinusoid riding on linear ramp

$$x(t) = x(t_i) + vt + A \cos\left(\frac{4\pi}{\lambda_0}vt\right) + B \sin\left(\frac{4\pi}{\lambda_0}vt\right)$$

- Iteratively solve for velocity
 - Use time window covering at least one wavelength of sinusoid ($\tau = 6$ ns)



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